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| Application/Control No. | Applicant(s)/Patent under Reexamination |
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| Class | Subclass | Date | Examiner | | |
| 123 | 295 | 8/31/2005 | ннн | | |
| 123 | 305 | 8/31/2005 | ннн | | |
| 123 | 90.11 | 8/31/2005 | ннн | | |
| 123 | 90.15 | 8/31/2005 | ннн | | |
| 123 | 90.16 | 8/31/2005 | ннн | | |
| 123 | 435 | 8/31/2005 | ннн | | |
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| SEARCH NOTES (INCLUDING SEARCH STRATEGY) | | | | |
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